

TLP108

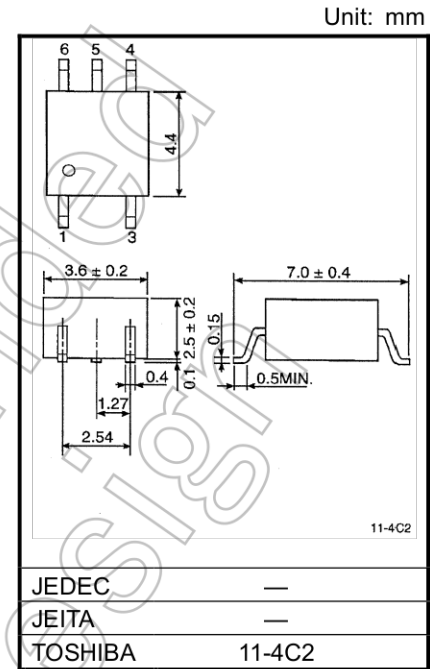
- Isolated bus drivers
- High speed line receivers
- Microprocessor system interfaces

The Toshiba TLP108 consists of an infrared emitting diode optically coupled to a high-gain, high-speed photodetector. The TLP108 is housed in a 6-pin MFSOP. With a totem-pole output, the TLP108 is capable of both sinking and sourcing current. The TLP108 has an internal Faraday shield, which provides a guaranteed common-mode transient immunity. The TLP108 has an inverting output. A noninverting-output version, the TLP105, is also available.

- Inverter logic type (totem-pole output)
- Guaranteed Performance Over temperature: -40 to 100°C
- Power Supply Voltage: 4.5 to 20 V
- Input Threshold Current: $I_{FHL} = 1.6 \text{ mA (max)}$
- Switching Time (t_{pLH}/t_{pHL}): 250 ns (max)
- Common mode transient immunity: 10 kV/μs
- Isolation Voltage: 3750 Vrms
- UL-recognized: UL 1577, File No.E67349
- cUL-recognized: CSA Component Acceptance Service No.5A File No.E67349
- VDE-approved: EN 60747-5-5 (Note1)
Note1 : When a VDE approved type is needed, Please designate the **Option(V4)**.

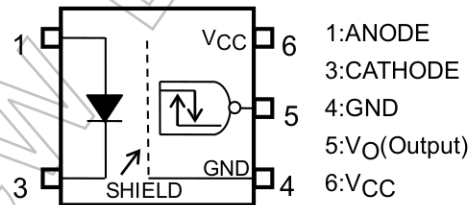
Truth Table

Input	LED	Tr1	Tr2	Output
H	ON	OFF	ON	L
L	OFF	ON	OFF	H

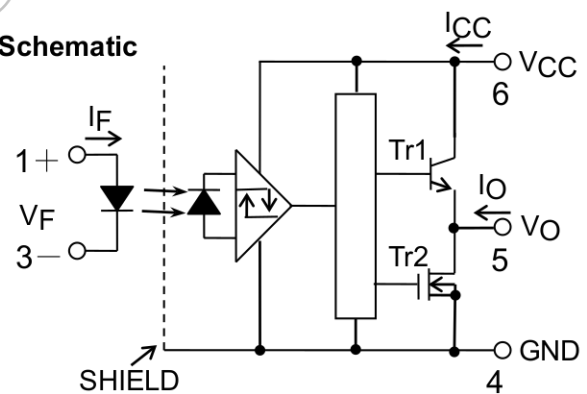


Weight: 0.09 g (typ.)

Pin Configuration (top View)



Schematic



0.1 μF bypass capacitor must be connected between pin 6 and 4.

Start of commercial production
2008-04

Recommended Operating Conditions

Characteristics	Symbol	Min	Typ.	Max	Unit
Input Current , ON	I _{F(ON)}	2	—	10	mA
Input Voltage , OFF	V _{F(OFF)}	0	—	0.8	V
Supply Voltage*	V _{CC}	4.5	—	20	V
Operating Temperature	T _{opr}	-40	—	100	°C
Fan-out (TTL Load)	N	—	—	4	—

* This item denotes operating range, not meaning of recommended operating conditions.

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
LED	Forward Current	I _F	20	mA
	Forward Current Derating (Ta ≥ 83°C)	ΔI _F /°C	-0.48	mA/°C
	Peak Transient Forward Current (Note 1)	I _{FPT}	1	A
	Input Power Dissipation	P _d	40	mW
	Reverse Voltage	V _R	5	V
DETECTOR	Output Current 1 (Ta ≤ 25°C)	I _{O1}	25/-15	mA
	Output Current 2 (Ta ≤ 100°C)	I _{O2}	5/-5	mA
	Output Current Derating (Ta ≥ 25°C)	ΔI _{O1} /°C	-0.26/-0.13	mA/°C
	Peak Output Current (Note 2)	I _{OP}	50/-50	mA
	Output Voltage	V _O	-0.5 to 20	V
	Output Power Dissipation	P _o	75	mW
	Supply Voltage	V _{CC}	-0.5 to 20	V
Operating Temperature Range		T _{opr}	-40 to 100	°C
Storage Temperature Range		T _{stg}	-55 to 125	°C
Lead Solder Temperature (10 s)		T _{sol}	260	°C
Isolation Voltage (AC, 60 s, R.H. ≤ 60 %) (Note 3)		BV _S	3750	V _{rms}

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Pulse width ≤ 1 μs, 300 pps.

Note 2: Pulse width ≤ 5 μs, duty cycle ≤ 0.025

Note 3: Device considered a two terminal device: pins 1 and 3 shorted together and pins 4, 5 and 6 shorted together.

Electrical Characteristics

(Unless otherwise specified, Ta = -40 to 100°C, VCC = 4.5 to 20 V)

Characteristics	Symbol	Test Circuit	Condition	Min	Typ.	Max	Unit	
Input Forward Voltage	V_F	—	$I_F = 10 \text{ mA}$, $T_a = 25 \text{ }^\circ\text{C}$	1.45	1.57	1.75	V	
Temperature Coefficient of Forward Voltage	$\Delta V_F / \Delta T_a$	—	$I_F = 10 \text{ mA}$	—	-2.0	—	mV/°C	
Input Reverse Current	I_R	—	$V_R = 5 \text{ V}$, $T_a = 25 \text{ }^\circ\text{C}$	—	—	10	μA	
Input Capacitance	C_T	—	$V = 0 \text{ V}$, $f = 1 \text{ MHz}$, $T_a = 25 \text{ }^\circ\text{C}$	—	100	—	pF	
Logic Low Output Voltage	V_{OL}	1	$I_{OL} = 3.5 \text{ mA}$, $I_F = 5 \text{ mA}$	—	0.2	0.6	V	
Logic High Output Voltage	V_{OH}	2	$I_{OH} = -2.6 \text{ mA}$, $V_F = 0.8 \text{ V}$	$V_{CC} = 4.5 \text{ V}$	2.7	4.0	—	V
				$V_{CC} = 20 \text{ V}$	17.4	19.0	—	
Logic Low Supply Current	I_{CCL}	3	$I_F = 5 \text{ mA}$	$V_{CC} = 20 \text{ V}$	—	—	3.0	mA
				$V_{CC} = 5.5 \text{ V}$	—	—	3.0	
Logic High Supply Current	I_{CCH}	4	$V_F = 0 \text{ V}$	$V_{CC} = 20 \text{ V}$	—	—	3.0	mA
				$V_{CC} = 5.5 \text{ V}$	—	—	3.0	
Logic Low Short Circuit Output Current (Note 1)	I_{OSL}	5	$I_F = 5 \text{ mA}$, $V_O = \text{GND}$	$V_{CC} = V_O = 5.5 \text{ V}$	15	80	—	mA
				$V_{CC} = V_O = 20 \text{ V}$	20	90	—	
Logic High Short Circuit Output Current (Note 1)	I_{OSH}	6	$V_F = 0 \text{ V}$	$V_{CC} = 5.5 \text{ V}$	-5	-15	—	mA
				$V_{CC} = 20 \text{ V}$	-10	-20	—	
Input Current Logic Low Output	I_{FHL}	—	$I_O = 3.5 \text{ mA}$, $V_O < 0.4 \text{ V}$	—	0.4	1.6	mA	
Input Voltage Logic High Output	V_{FLH}	—	$I_O = -2.6 \text{ mA}$, $V_O > 2.4 \text{ V}$	0.8	—	—	V	
Input Current Hysteresis	I_{HYS}	—	$V_{CC} = 5 \text{ V}$	—	0.05	—	mA	

*All typical values are at $T_a = 25 \text{ }^\circ\text{C}$

Note 1: Duration of output short circuit time should not exceed 10 ms.

Isolation Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Typ..	Max	Unit
Capacitance input to output	C_S	$V_S = 0 \text{ V}$, $f = 1 \text{ MHz}$	—	0.8	—	pF
Isolation resistance	R_S	R.H. $\leq 60 \%$, $V_S = 500 \text{ V}$	1×10^{12}	10^{14}	—	Ω
Isolation voltage	BV_S	AC, 60 s	3750	—	—	V_{rms}

Note : Device considered a two terminal device: pins 1 and 3 shorted together and pins 4, 5 and 6 shorted together..

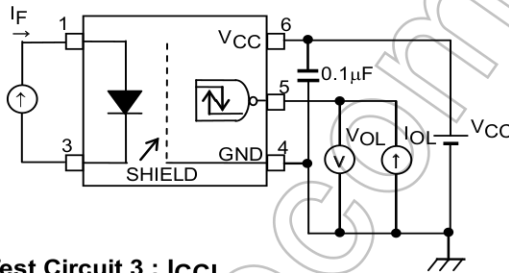
Switching Characteristics

(Unless otherwise specified, $T_a = -40$ to 100°C , $V_{CC} = 4.5$ to 20 V)

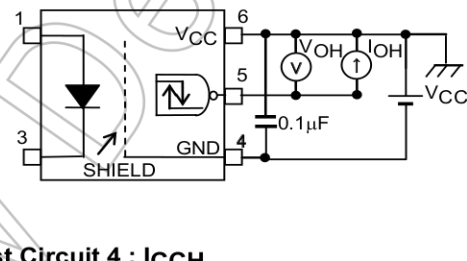
Characteristics	Symbol	Test Circuit	Condition	Min	Typ.	Max	Unit
Propagation Delay Time to Logic High output	t_{pLH}	7, 8	$I_F = 3 \rightarrow 0\text{ mA}$	30	150	250	ns
Propagation Delay Time to Logic Low output	t_{pHL}		$I_F = 0 \rightarrow 3\text{ mA}$	30	150	250	ns
Switching Time Dispersion between ON and OFF	$ t_{pHL} - t_{pLH} $		—	—	—	220	ns
Rise Time (10 – 90 %)	t_r		$I_F = 3 \rightarrow 0\text{ mA}$, $V_{CC} = 5\text{ V}$	—	30	75	ns
Fall Time (90 – 10 %)	t_f		$I_F = 0 \rightarrow 3\text{ mA}$, $V_{CC} = 5\text{ V}$	—	30	75	ns
Common Mode transient Immunity at High Level Output	CM_H		9	$V_{CM} = 1000\text{ V}_{p-p}$, $I_F = 0\text{ mA}$, $V_{CC} = 20\text{ V}$, $T_a = 25^\circ\text{C}$	-10000	—	—
Common Mode transient Immunity at Low Level Output	CM_L	$V_{CM} = 1000\text{ V}_{p-p}$, $I_F = 5\text{ mA}$, $V_{CC} = 20\text{ V}$, $T_a = 25^\circ\text{C}$		10000	—	—	$\text{V}/\mu\text{s}$

*All typical values are at $T_a = 25^\circ\text{C}$

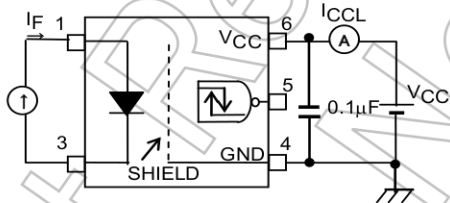
Test Circuit 1 : VOL



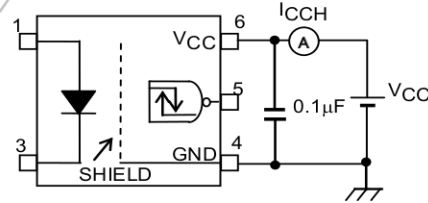
Test Circuit 2 : VOH



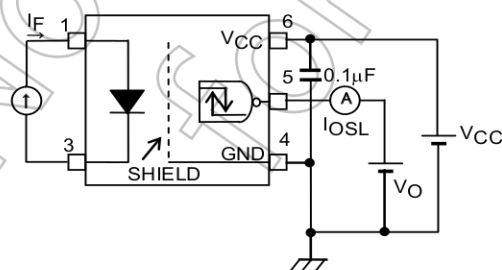
Test Circuit 3 : ICCL



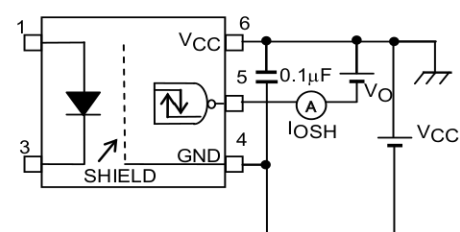
Test Circuit 4 : ICCH



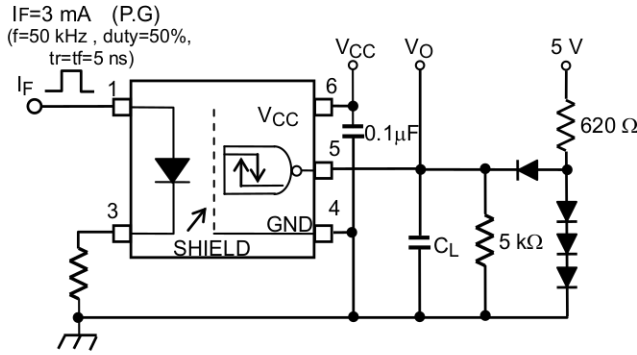
Test Circuit 5 : IOSL



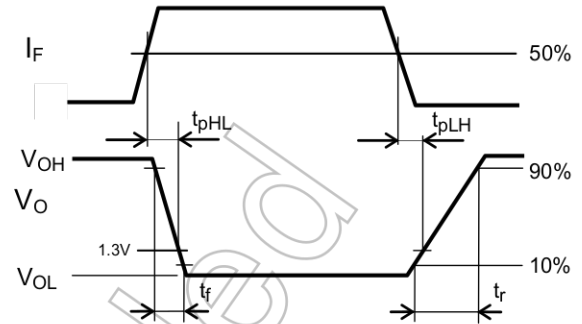
Test Circuit 6 : IOSH



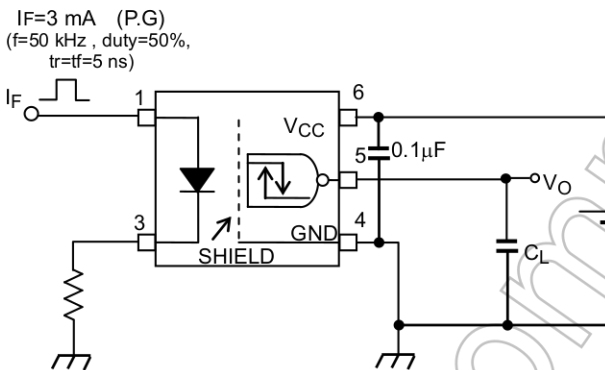
Test Circuit 7: Switching Time Test Circuit



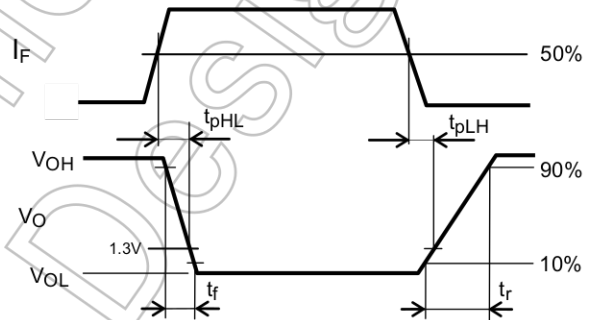
C_L is approximately 15 pF which includes probe and stray wiring capacitance.
 P.G.: Pulse generator



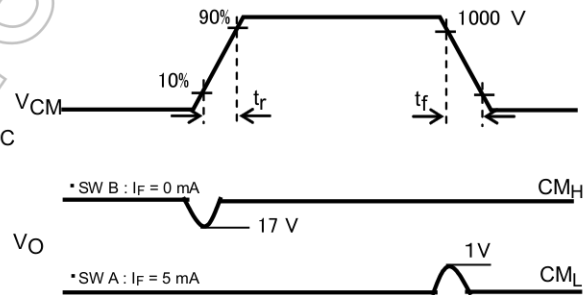
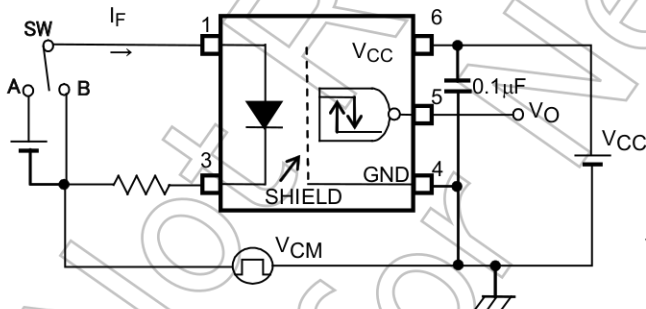
Test Circuit 8: Switching Time Test Circuit



C_L is approximately 15 pF which includes probe and stray wiring capacitance.
 P.G.: Pulse generator



Test Circuit 9: Common Mode Transient Immunity Test Circuit



$$CM_H = \frac{800(V)}{t_f(\mu s)} \quad CM_L = \frac{800(V)}{t_r(\mu s)}$$

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